

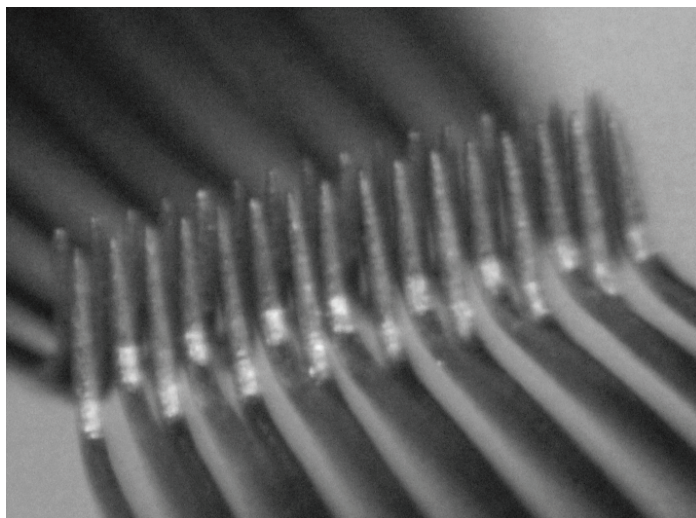
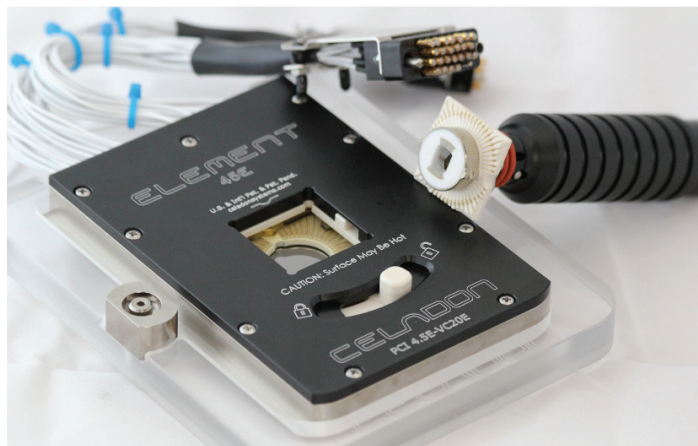
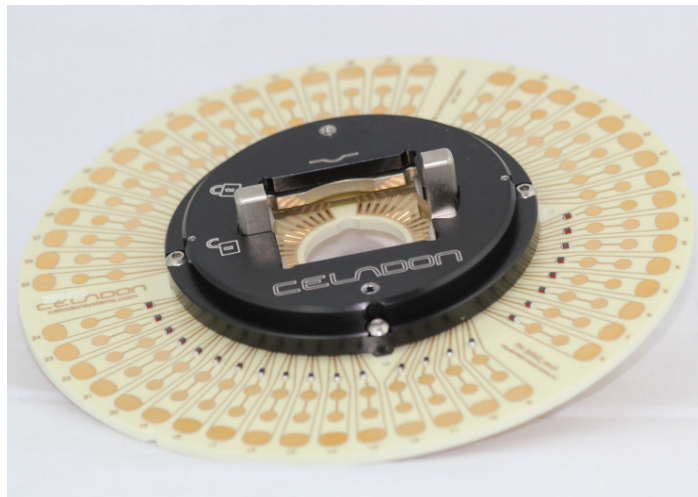
UNIFY YOUR ENTIRE LAB AND FAB

## VC20 ELEMENT SERIES

Modeling & Characterization, Production Parametric Test, and Single-Site Wafer Level Reliability

The VC20 Element Series probe card is the size of a coin, and can be quickly and easily installed into multiple interfaces for various automatic and analytical probe stations for modeling and characterization, production parametric test, and wafer level reliability testing. Cards can be configured with up to 48 probes, in either single or dual layer, with nearly vertical probes to minimize scrub lengths on pads, allowing VC20s to probe pads as small as 30um.

The same VC20 card can be used across multiple Element Series interfaces compatible with many industry-standard probing platforms. Use the same probe card for multiple tests, or change out VC20s for different layouts on the same prober. Leave the interface in place, and just install the VC20 - minimizing the possibility of triboelectric or interconnect issues that can occur during typical probe card changes.



ONE TINY PROBE  
CARD TO UNIFY  
YOUR ENTIRE LAB  
AND FAB